Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/632,037	LERCHE ET AL.
Examiner	Art Unit
B. Chen ·	1762

	SEARCHED					
	JLAN	CHED	·			
Class	Subclass	Date	Examiner			
updated	previous	8/18/2006	вс			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
427	249.1	8/18/2006	ВС	
	249.6			
	294			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
east		8/18/2006	вс